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**Koort, Ants** Тезисы докладов научно-технической конференции, посвященной Дню радио 1974 / с. 15-16 [https://www.ester.ee/record=b1294751\\*est](https://www.ester.ee/record=b1294751*est)

## **Строитель Аувереской электростанции выплатил Enefit Power штраф в размере 130 млн евро**

stena.ee 2022 [Строитель Аувереской электростанции выплатил Enefit Power штраф в размере 130 млн евро](#)